

### IEC QUALITY ASSESSMENT SYSTEM (IECQ)

covering Electronic Components,
Assemblies, Related Materials and Processes

For rules and details of the IECQ visit www.iecq.org

# IECQ Certificate of Approval Independent Testing Laboratory

IECQ Certificate No.: IECQ-L DEKRA 16.0002 Issue No.: 1 Status: Current

Supersedes: <u>IECQ-L NSAIUS 10.0003 Issue 4</u> **Issue Date: 2016/08/17 Org Issue: 2016/08/17** 

CB Reference No.: DEKRA-T5-001 Expiration: 2019/08/16

#### Integrated Service Technology, Inc.

1F, No. 19 Pu-Ding road Hsin-Chu City, 300 Taiwan

The organization, facilities and procedures have been assessed and found to comply with the applicable requirements for Independent Testing Laboratory organization approval, in support of the IECQ system, which is in accordance with the Basic Rules IECQ 01 and Rules of Procedure IECQ 03-6 "Independent Testing Laboratory Assessment Program Requirements" of the IEC Quality Assessment System for Electronic Components (IECQ) and applicable requirements of ISO/IEC 17025: 2005 for the testing of electronic components under the IECQ.

Scope:

Consumer / Commercial / Industrial (JESD 47) and Automotive / Military accelerated environment reliability stress tests, accelerated lifetime simulation tests, electromagnetic compatibility and electrostatic discharge test, and 2nd level integration platform service of Electronic Components, Assemblies, and Related Materials

Failure and material analysis of Semiconductor IC, Electronic Components and PCB/PCBA

See attached Schedule of Scope

-- Attached Schedule: IECQ-L DEKRA 16.0002-S Rev1.1.pdf --

Approved by Certification Body (CB): DEKRA Certification B.V.

Meander 1051

Arnhem

Netherlands

Authorized person:

Ted Gaertner







The validity of this certificate is maintained through on-going surveillance audits by the IECQ CB issuing this certificate.

This Certificate of Conformity may be suspended or with drawn in accordance with the  $\,$ 

Rules of Procedure of the IECQ System and its Schemes.

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# Schedule of Scope to Certificate of Approval

## **Independent Testing Laboratory**

IECQ Certificate No.: IECQ-L DEKRA 16.0002
CB Certificate No.: DEKRA-T5-001

Schedule Number: IECQ-L DEKRA 16.0002-S Rev No.: 1.1 Revision Date: 2016/08/16 Page 1 of 2

- 1. Consumer / Commercial / Industrial (JESD 47) and Automotive / Military
  - accelerated environment reliability stress tests
  - accelerated lifetime simulation tests
  - · electromagnetic compatibility and electrostatic discharge test
  - · 2nd level integration platform service

of Electronic Components, Assemblies, and Related Materials

2. Failure and material analysis of semiconductor IC, electronic components and PCB/PCBA

Description test	Standard	Remarks
Consumer / Commercial / Industrial (JESD 47) and Automotive / Military accelerated environment reliability stress tests (Including: Pre-condition / MSL / Accelerated Temperature-Humidity test / Temperature-Humidity with bias test / Temperature Cycling test / Power and temperature cycling / Temperature storage test / IOL / Salt)	J-STD-020, JESD22-A101/A102/ A106/A107/A110/A113/A118/A119; IEC-60068-2-1/2/3/14/ 38/52, MIL-STD-202/750/810/883,JESD JP001; EIA-364-32C, EIAJ ED-4701, AEC-Q200-001 /004; AEC-Q005/Q006,	Or customer specified test
Consumer/ Commercial / Industrial (JESD 47) and Automotive / Military accelerated lifetime simulation tests. (Including: Temperature, Bias, and Operating Life test / early life failure rate / Endurance and Data retention test / Electro-Migration / Short circuit / Miscellaneous test / Gate Leakage test)	JESD22-A108/A117, JESD61, MIL-STD-202/750/810/883, AEC-Q100-005/006/008/012, AEC-Q101-004/006, Customer standards	Or customer specified test
Consumer / Commercial / Industrial (JESD 47) and Automotive / Military electromagnetic compatibility and electrostatic discharge test. (Including : IC EMI / IC EMS / HBM / MM / CDM / Latch Up / ESD Gun / Surge Test)	SAE J1752/1-3, IEC 61967/1-3, JEDEC22-A114/A115/C101, EIA/JESD78, ANSI JEDEC ESDA JS001/JS002; ISO-10605, AEC-Q100-002/003/004/011, AEC-Q101-001/002/005, AEC-Q200-002/007,JEITA ED4701; IEC61000-4-2, MIL-STD-202/750/810/883	Or customer specified test

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Description test	Standard	Remarks
Consumer / Commercial / Industrial (JESD 47) and Automotive / Military 2nd level integration platform service.  (Including: Pre-SMT/SMT / Temperature Cycling test / Temperature-Humidity test / Drop / Shock / Bending / Pull and Push test / Solderability / Press / Shear / Hardness / RCA / Durability / Peeling / Terminal Strength / Resistance to Solvents / Resistance to Solder Heat / Hermeticity)	IPC-7525/9701/9702/9708/A-610, JESD22-A101/A104/A106/A109/ A111/B100/B102/B103/B105/B106/B 107/B108/B110/B111/B113/B115/B1 16/B117; EIAJ ED-4702, EIA-364-09/13; AEC-Q100-001/010; AEC-Q101-003, AEC-Q200-003/005/ 006; MIL-STD-202/750/810/883, J-STD-002/003; ASTM D3363, ASTM F2357; SEMI G86-0303, IEC 60068-2-21; IPC-TM-650,	Or customer specified test
Failure and material analysis of semiconductor IC, electronic components and PCB/PCBA, including FIB (Focused Ion Beam), Electrical Analysis, Sample Preparation (Decap, X-section, etc), NDE (Non-destructive Engineering), Physical & Chemical Analysis (Including Hazardous Substances) and IC package.	IEC62321, IPC-TM-650, IPC-610, J-STD-020, JEDEC-C201, EIA-469, EN14582.	Or customer specified test

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